## Notice of References Cited

Application/Control No. 10/676,643	Reexamination	Applicant(s)/Patent Under Reexamination KIM, WAN SHICK		
Examiner	Art Unit	_		
Bryan R. Muller	3723	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,710,069	01-1998	Farkas et al.	438/7
	В	US-6,275,290	08-2001	Cerni et al.	356/335
	С	US-5,191,388	03-1993	Kilham, Lawrence B.	356/335
	D	US-6,347,976	02-2002	Lawton et al.	451/6
	Ε	US-6,319,099	11-2001	Tanoue et al.	451/60
	F	US-4,669,230	06-1987	Suzuki et al.	451/2
	G	US-3,596,839	08-1971	Putman, Richard E. J.	241/20
	н	US-6,595,829	07-2003	Melcer, Chris	451/5
	-	US-6,410,441	06-2002	Niu, Pao-Kang	438/692
	7	US-6,048,256	04-2000	Obeng et al.	451/60
	К	US-4,784,295	11-1988	Holmstrand, Allan L.	222/148
	L	US-5,561,520	10-1996	Williams, Richard A.	356/335
	М	US-6,544,109	04-2003	Moore, Scott E.	451/60

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	KR 2002054538 A	07-2002	Korea, Republic	CHOI et al.	G01N 21/33
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.